Search	Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
09/710,162	ONYON ET AL.
Examiner	Art Unit
Haresh Patel	2154

	SEARCHED				
Class	Subclass	Date	Examiner		
709	200-203, 217-228,	drol06	H.P.		
709	230-232				
709	243,244				
707	204				
719	310,311				
719	317,318				
7-18	100,105		-		
455	415				
370	254				
707	201,203				
708	204				
707	10				
345	36 2				
370	359	1	1		

INTERFERENCE SEARCHED				
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